

GPI8HIRGIC

GaN Power IC in DFN5x6 Package

Preliminary Datasheet version: 1.0

D

S

Vin2 Vin1

Vcc (6-15V)

Vcc

D

S

IC

NC

Vin2

Vin1

Features

BV _{dss}	R _{dson}	l _{ds}	
650V	175 mΩ	7.5 A	

- Edge-triggered high-side power IC
- Small transformer isolation
- Wide Vcc range
- Low Rds and high dv/dt capability
- Extremely low input/output capacitance
- Fast switching
- Low Profile

Applications

- High-side switch in switching power applications
- Power adapters and power delivery chargers

Description

These devices are power IC based on 650 V Power GaN HEMTs using proprietary (US patent pending) E-mode GaN on silicon technology. The gate driver is integrated with the main power transistor resulting in fast switching, high system power density and low cost. Edge triggering narrow pulse is used to control device turn-on/off. This results in high noise immunity and small and inexpensive transformer for isolation and level shifting for the high-side switch in a half bridge application.



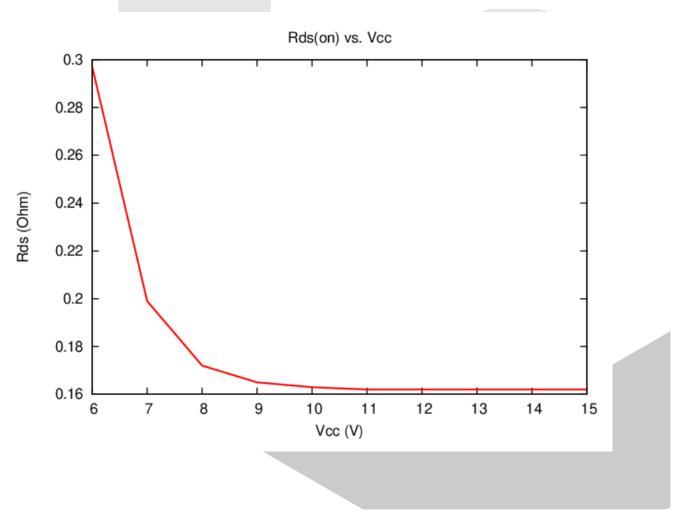
Basic Parameters			Test data				
	Parameters		Conditions	Min	Typical	Max	Unit
1	BV _{dss}	Drain-Source breakdown voltage	V _{gs} =0V I _d =10uA		650		V
2	R _{dson}	Static drain-source on resistance, $T_C = 25^{\circ}C$	V _{gs} =6V I _d =1.8A	165	175	300	mΩ
3	Vcc	Drive supply voltage		6	10	15	V
4	Vin1	Turn-off narrow pulse triggering pulse	Pulse width 100ns-300ns	3	5	8	V
5	Vin2	Turn-on narrow pulse triggering pulsePulse wi 100ns-30		3	5	8	V
Switching Performance			Test data				
	Parameters		Conditions	Min	Typical	Max	Unit
1	t _{d(on)}	Turn-on delay time	V _{ds} =385V		15		ns
2	tr	Vds rise time (turn-off)Id=1.6ATurn-off delay timeVin1/2=5V			8		ns
3	t _{d(off)}				10		ns
4	t _f	Vds Fall time (turn-on)	V _{dd} =6.5V		12		ns

Device Characteristics



Electrical Performance

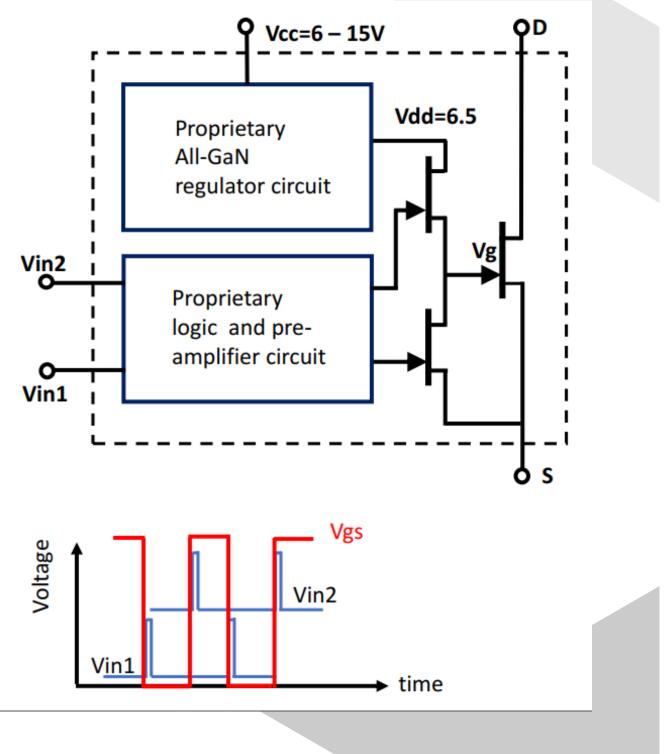
Rds(on) vs. Vdd at Id=15mA



For more information, visit us at: www.iganpower.com, or contact us at sales@iganpower.com



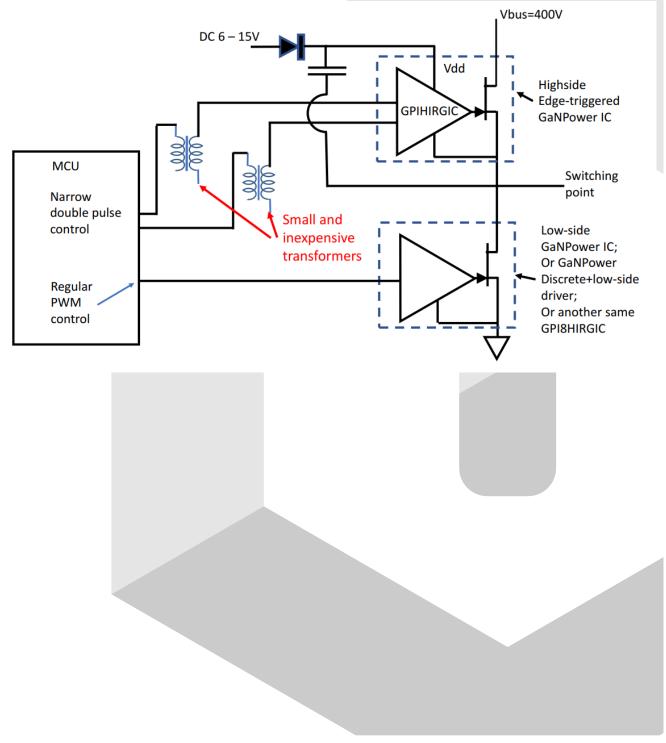
Internal Schematic and waveforms



For more information, visit us at: www.iganpower.com, or contact us at sales@iganpower.com



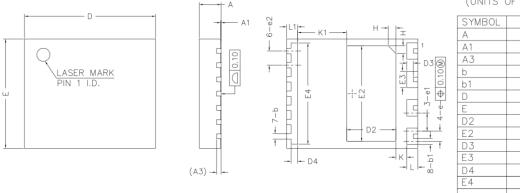
Typical Application Circuit (Conceptual)





_ _ _

Package Information



COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX		
A	0.90	1.00	1.10		
A1	0.00	0.02	0.05		
A3	0.203REF				
b	0.20	0.25	0.30		
b1	0.225	0.275	0.325		
D	5.90	6.00	6.10		
E	4.90	5.00	5.10		
D2	2.15	2.25	2.35		
E2	4.27	4.37	4.47		
D3	0.20	0.30	0.40		
E3	0.65	0.75	0.85		
D4	0.20	0.30	0.40		
E4	4.525	4.625	4.725		
е	0.375	0.475	0.575		
e1	0.725	0.825	0.925		
e2	0.55	0.65	0.75		
Н	0.35REF				
К	0.35	0.50	0.65		
K1	2.10	2.25	2.40		
L	0.40	0.50	0.60		
L1	0.40	0.50	0.60		





GaN HEMT Frequently Asked Questions

1	Q: Can we do pin to pin switch for silicon MOSFET or IGBT?
	A: The short answer is no. GaN HEMT power devices are far superior than the best silicon
	devices such as super junction MOSFETs. However, due to different requirements of gate
	driving voltage and extremely high dv/dt slew rate, special drivers and optimized PCB layouts
	are recommended to minimize the impact from circuit parasitics. Some packaging forms such
	as GaNPower's DFN packaged devices offer both sense and force for the source terminal. Also,
	for traditional TO220 packages, please be advised that the pins are arranged as Gate – Source
	-Drain, and the thermal pad is connected to the source instead of drain.
2	Q: Are GaN power devices reliable?
	A: GaN power HEMTs have been tested by GaNPower and many other vendors, users and
	testing facilities to be as reliable (if not better than) silicon counterparts.
3	Q: How do GaN power devices compare with SiC?
	A: Currently GaN power HEMT devices are most suitable for low to medium voltage (\leq 1200V)
	and power (<20KW) applications. GaN is the ideal choice for high frequency applications. SiC
	devices are better choice for high voltage and high-power applications (>20KW).
4	Q: Do we need to parallel an FRD for applications such as inverters?
	A: GaN devices are different from silicon MOSFET or IGBT in that they have no inherent PN
	junction diodes that cause reverse recovery issue. User do not need to parallel an FRD for the
	purpose of suppressing the body diode reverse recovery effect, since GaN HEMT can operate
	in both first and third quadrants. However, care should be taken for the dead time power loss
	since the Vsd voltage of GaN HEMT is usually close to 2V. This is especially true when a negative
	gate voltage is applied.
5	Q: Can we parallel GaN HEMT devices?
	A: Yes, GaN HEMT is ideal for paralleling, due to positive temperature coefficient of Rdson
	and slightly positive temperature coefficient of threshold voltage.